Se	earch	Notes	

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/026,021	HITOSHI ET AL.	
Examiner	Art Unit	
MISOOK YII Ph D	1642	

	SEARCHED		
Class	Subclass	Date	Examiner
435	5	3/18/2005	MY
	6	3/18/2005	MY
	7.1	3/18/2005	MY
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
West, Dialog (155), inventors (NPL, PALM). SEQ ID NOs 1, and 2, see enclosures	3/18/2005	MY
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